

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L7	12	("20010012688"   "20020027288"   "5330614"   "5545585"   "5631185"   "5763306"   "5933724"   "6001683"   "6194309"   "6215187"   "6228762"   "6239022").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/02/14 14:49
L9	1013	capacitor with (form\$4 or creat\$4 or manufactur\$4 or fabriacat\$4) and (etch\$4 adj stop\$3) and anneal\$4	USPAT; EPO; JPO; IBM_TDB	OR	OFF	2005/02/14 14:58
L10	9	(US-5545585-\$ or US-5763286-\$ or US-6001683-\$ or US-6215187-\$ or US-6548853-\$ or US-6566188-\$ or US-6586312-\$ or US-6682984-\$ or US-6759704-\$).did.	USPAT	OR	OFF	2005/02/14 14:52
L11	340	9 and (wet\$4 adj etch\$4) and (dry\$4 adj etch\$4)	USPAT; EPO; JPO; IBM_TDB	OR	OFF	2005/02/14 14:53
L12	322	11 and (open\$4 or width or size)	USPAT; EPO; JPO; IBM_TDB	OR	OFF	2005/02/14 14:54
L13	145	12 and (dopant\$4 or ion) and (etch\$4 adj rate)	USPAT; EPO; JPO; IBM_TDB	OR	OFF	2005/02/14 14:55
L14	144	13 not (7 10)	USPAT; EPO; JPO; IBM_TDB	OR	OFF	2005/02/14 14:55
L15	128	14 and (method or process) and ((upper or top or first or second) adj3 layer)	USPAT; EPO; JPO; IBM_TDB	OR	OFF	2005/02/14 14:56
L17	125	15 and (plug or contact)	USPAT; EPO; JPO; IBM_TDB	OR	OFF	2005/02/14 14:57
L20	39	17 and (capacitor with (form\$4 or creat\$4 or manufactur\$4 or fabriacat\$4).ab. and (etch\$4 adj stop\$3) and anneal\$4)	USPAT; EPO; JPO; IBM_TDB	OR	OFF	2005/02/14 15:00
S1	1	"20040085708"	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/07/26 18:21
S2	5	oh-jung-hwan.in.	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/07/26 19:20
S3	22	hwang-ki-hyun.in.	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/07/26 19:20
S4	17	park-jae-young.in.	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/07/26 19:20
S5	31	hwang-in-seak.in.	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/07/26 19:20
S6	85	park-young-wook.in.	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/07/26 19:20
S7	2	"6700153"	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/07/26 19:22

S8	67	((oh-jung-hwan.in. hwang-ki-hyun.in. park-jae-young.in. hwang-in-seak.in. park-young-wook.in.) and (capacitor with (electrode or plate)))	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/07/26 19:31
S9	14	((oh-jung-hwan.in. hwang-ki-hyun.in. park-jae-young.in. hwang-in-seak.in. park-young-wook.in.) and (capacitor with (electrode or plate))) and (etch\$4 with rate)	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/07/26 19:32
S10	10	(((oh-jung-hwan.in. hwang-ki-hyun.in. park-jae-young.in. hwang-in-seak.in. park-young-wook.in.) and (capacitor with (electrode or plate))) and (etch\$4 with rate)) and plug	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/07/26 19:23
S11	6	(((oh-jung-hwan.in. hwang-ki-hyun.in. park-jae-young.in. hwang-in-seak.in. park-young-wook.in.) and (capacitor with (electrode or plate))) and (etch\$4 with rate)) and plug) and (etch adj stop\$)	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/07/26 19:32
S12	17	((0018248 "0019107 "0028553 "0034114 "5100825 "5434812 "5468684 "5545585 "5763286 "5885865 "5943581 "0000596 "6022772 "6168987 "6215187 "6222722 "6258689 "6268244 "6271084 "6312986 "6586312 "6682984").PN.) and (capacitor with (electrode or plate))	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/07/26 19:32
S13	7	((0018248 "0019107 "0028553 "0034114 "5100825 "5434812 "5468684 "5545585 "5763286 "5885865 "5943581 "0000596 "6022772 "6168987 "6215187 "6222722 "6258689 "6268244 "6271084 "6312986 "6586312 "6682984").PN.) and (capacitor with (electrode or plate)) and (etch adj stop\$)	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/07/26 19:32
S14	2	(((0018248 "0019107 "0028553 "0034114 "5100825 "5434812 "5468684 "5545585 "5763286 "5885865 "5943581 "0000596 "6022772 "6168987 "6215187 "6222722 "6258689 "6268244 "6271084 "6312986 "6586312 "6682984").PN.) and (capacitor with (electrode or plate)) and (etch adj stop\$)) and (etch\$4 with rate)	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/07/26 19:37
S15	4	("5053351"   "5164881"   "5185282"   "5403767").PN.	USPAT	OR	ON	2004/07/26 19:36
S16	5	(((0018248 "0019107 "0028553 "0034114 "5100825 "5434812 "5468684 "5545585 "5763286 "5885865 "5943581 "0000596 "6022772 "6168987 "6215187 "6222722 "6258689 "6268244 "6271084 "6312986 "6586312 "6682984").PN.) and (capacitor with (electrode or plate)) and (etch adj stop\$)) not (((0018248 "0019107 "0028553 "0034114 "5100825 "5434812 "5468684 "5545585 "5763286 "5885865 "5943581 "0000596 "6022772 "6168987 "6215187 "6222722 "6258689 "6268244 "6271084 "6312986 "6586312 "6682984").PN.) and (capacitor with (electrode or plate)) and (etch adj stop\$)) and (etch\$4 with rate)	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/07/26 19:48
S17	5	("5656536"   "5770499"   "5851898"   "5869367"   "5891772").PN.	USPAT	OR	ON	2004/07/26 19:42
S18	10	(((0018248 "0019107 "0028553 "0034114 "5100825 "5434812 "5468684 "5545585 "5763286 "5885865 "5943581 "0000596 "6022772 "6168987 "6215187 "6222722 "6258689 "6268244 "6271084 "6312986 "6586312 "6682984").PN.) and (capacitor with (electrode or plate)) not (((0018248 "0019107 "0028553 "0034114 "5100825 "5434812 "5468684 "5545585 "5763286 "5885865 "5943581 "0000596 "6022772 "6168987 "6215187 "6222722 "6258689 "6268244 "6271084 "6312986 "6586312 "6682984").PN.) and (capacitor with (electrode or plate)) and (etch adj stop\$))	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/07/26 19:48
S19	4	("5597756"   "5658818"   "5936308"   "6031293").PN.	USPAT	OR	ON	2004/07/27 10:11
S20	4	"6215187".URPN.	USPAT	OR	ON	2004/07/27 10:11
S21	8	("5330614"   "5545585"   "5631185"   "6001683"   "6194309"   "6215187"   "6228762"   "6239022"   "2001/0012688"   "2002/0027288").PN.	USPAT	OR	ON	2004/07/27 10:12
S22	0	"6528368".URPN.	USPAT	OR	ON	2004/07/27 10:14
S23	0	"6528368".URPN.	USPAT	OR	ON	2004/07/27 10:14

S24	16	(((farbricat\$4 or form\$4 or creat\$4) near2 capacitor) and opening and (wet adj etching) and (etch adj stop) and plug) and ((farbricat\$4 or form\$4 or creat\$4) near2 capacitor).ti.) not (((5597756"   "5658818"   "5936308"   "6031293").PN.) "6215187".URPN. ((5330614"   "5545585"   "5631185"   "6001683"   "6194309"   "6215187"   "6228762"   "6239022"   "2001/0012688"   "2002/0027288").PN.))	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/07/27 11:14
S25	144	((farbricat\$4 or form\$4 or creat\$4) near2 capacitor) and opening and (wet adj etching) and (etch adj stop) and plug	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/07/27 13:30
S26	16	(((farbricat\$4 or form\$4 or creat\$4) near2 capacitor) and opening and (wet adj etching) and (etch adj stop) and plug) and ((farbricat\$4 or form\$4 or creat\$4) near2 capacitor).ti.	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/07/27 13:30
S27	13	((((farbricat\$4 or form\$4 or creat\$4) near2 capacitor) and opening and (wet adj etching) and (etch adj stop) and plug) and ((farbricat\$4 or form\$4 or creat\$4) near2 capacitor).ti.) not (((5597756"   "5658818"   "5936308"   "6031293").PN.) "6215187".URPN. ((5330614"   "5545585"   "5631185"   "6001683"   "6194309"   "6215187"   "6228762"   "6239022"   "2001/0012688"   "2002/0027288").PN.)) and (dry adj etch\$4)	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/07/27 13:30
S28	3	((((farbricat\$4 or form\$4 or creat\$4) near2 capacitor) and opening and (wet adj etching) and (etch adj stop) and plug) and ((farbricat\$4 or form\$4 or creat\$4) near2 capacitor).ti.) not (((((farbricat\$4 or form\$4 or creat\$4) near2 capacitor) and opening and (wet adj etching) and (etch adj stop) and plug) and ((farbricat\$4 or form\$4 or creat\$4) near2 capacitor).ti.) not (((5597756"   "5658818"   "5936308"   "6031293").PN.) "6215187".URPN. ((5330614"   "5545585"   "5631185"   "6001683"   "6194309"   "6215187"   "6228762"   "6239022"   "2001/0012688"   "2002/0027288").PN.)) and (dry adj etch\$4))	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/07/27 13:31
S29	128	(((farbricat\$4 or form\$4 or creat\$4) near2 capacitor) and opening and (wet adj etching) and (etch adj stop) and plug) not (((farbricat\$4 or form\$4 or creat\$4) near2 capacitor) and opening and (wet adj etching) and (etch adj stop) and plug) and ((farbricat\$4 or form\$4 or creat\$4) near2 capacitor).ti.)	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/07/27 13:31
S30	27	((((farbricat\$4 or form\$4 or creat\$4) near2 capacitor) and opening and (wet adj etching) and (etch adj stop) and plug) not (((farbricat\$4 or form\$4 or creat\$4) near2 capacitor) and opening and (wet adj etching) and (etch adj stop) and plug) and ((farbricat\$4 or form\$4 or creat\$4) near2 capacitor).ti.)) and ((etch adj stop) with expose)	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/07/27 13:31
S31	38	((((farbricat\$4 or form\$4 or creat\$4) near2 capacitor) and opening and (wet adj etching) and (etch adj stop) and plug) not (((farbricat\$4 or form\$4 or creat\$4) near2 capacitor) and opening and (wet adj etching) and (etch adj stop) and plug) and ((farbricat\$4 or form\$4 or creat\$4) near2 capacitor).ti.)) and ((etch adj stop) with expose\$3)	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/07/27 13:31
S32	38	((((((farbricat\$4 or form\$4 or creat\$4) near2 capacitor) and opening and (wet adj etching) and (etch adj stop) and plug) not (((farbricat\$4 or form\$4 or creat\$4) near2 capacitor) and opening and (wet adj etching) and (etch adj stop) and plug) and ((farbricat\$4 or form\$4 or creat\$4) near2 capacitor).ti.)) and ((etch adj stop) with expose\$3)) and (plug)	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/07/27 16:31
S33	137	oh-jung-hwan.in. hwang-ki-hyun.in. park-jae-young.in. hwang-in-seak.in. park-young-wook.in.	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/07/27 16:32
S34	22	("0018248" "0019107" "0028553" "0034114" "5100825" "5434812" "5468684" "5545585" "5763286" "5885865" "5943581" "000596" "6022772" "6168987" "6215187" "6222722" "6258689" "6268244" "6271084" "6312986" "6586312" "6682984").PN.	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/07/27 16:32

S35	33	(((((farbricat\$4 or form\$4 or creat\$4) near2 capacitor) and opening and (wet adj etching) and (etch adj stop) and plug) not (((farbricat\$4 or form\$4 or creat\$4) near2 capacitor) and opening and (wet adj etching) and (etch adj stop) and plug) and ((farbricat\$4 or form\$4 or creat\$4) near2 capacitor).ti.)) and ((etch adj stop) with expose\$3)) and (plug)) not ((oh-jung-hwan. in. hwang-ki-hyun.in. park-jae-young.in. hwang-in-seak.in. park-young-wook.in.)) (("0018248" "0019107" "0028553" "0034114" "5100825" "5434812" "5468684" "5545585" "5763286" "5885865" "5943581" "0000596" "6022772" "6168987" "6215187" "6222722" "6258689" "6268244" "6271084" "6312986" "6586312" "6682984").PN.))\"	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/07/27 16:32
S36	17	"6136643"	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/07/27 19:36

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## Drafts

- 17 and !
- Pending
- Active
  - L7: (12) Backward citation search 1
  - L8: (1013) capacitor with (form\$4 or creat\$4 or manufa\$4 or fabri\$4 or februar\$4 or februar\$4).ab. and (etch\$4 adj stop\$3) and anneal\$4
  - L10: (9) US-5545585-5 or US-5783386-5 or US-6001683-5
  - L11: (340) 9 and (wet\$4 adj etch\$4) and (dry\$4 adj etch\$4)
  - L12: (322) 11 and (open\$4 or width or size)
  - L13: (145) 12 and (dipant\$4 or ion) and (etch\$4 adj rat\$4)
  - L14: (144) 13 not (7 16)
  - L15: (108) 14 and (method or process) and ((upper or top\$4 adj etch\$4) and (method or process))
  - L17: (125) 15 and (plug or contact)
  - L20: (33) 17 and (capacitor with (form\$4 or creat\$4 or manufa\$4 or fabri\$4 or februar\$4 or februar\$4).ab. and (etch\$4 adj stop\$3) and anneal\$4)

## Failed

## Saved

- S1: (1) "2008CC085708"
- S2: (5) oh-jung-hwan.in.
- S3: (12) hwang-ki-hyun.in.

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17 and (capacitor with (form\$4 or creat\$4 or manufa\$4 or fabri\$4 or februar\$4 or februar\$4).ab. and (etch\$4 adj stop\$3) and anneal\$4)

#	PF	P	Document ID	Issue Date	Pages	Title	Current OR	Current X-
1	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6929191	20041207	28	Trench capacitor with an insulation collar and method for producing a trench capacitor	438/247	438/2437
2	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6792062	20040928	63	Semiconductor memory device having large storage capacity and minimal step height between memory cell and peripheral circuits	257/296	257/2442
3	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6731134	20040314	63	Semiconductor memory device and manufacturing method thereof	257/296	257/3017
4	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6773330	20040310	35	Method of forming an FeRAM capacitor having a bottom electrode diffusion barrier	438/3	257/3087
5	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6752219	20040222	51	Method of manufacturing semiconductor integrated circuit devices having a memory device with a reduced bit line stray capacity and such semiconductor integrated circuit device	438/253	257/221.0
6	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6574081	20040106	38	Infrared detecting element, infrared two-dimensional image sensor, and method of manufacturing the same	250/338.2	
7	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6569611	20031203	8	Method to form a corrugated structure for enhanced capacitance with plurality of boro-phospho silicate glass including germanium	438/398	257/221.0
8	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6536748	20031203	36	FeRAM capacitor post stack etch clean/repair	438/3	257/221.0
9	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6530498	20031121	34	Method of patterning a FeRAM capacitor with a sidewall during bottom electrode etch	438/3	257/221.0
10	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6535435	20031121	37	Infrared detecting element, infrared two-dimensional image sensor, and method of manufacturing the same	438/3	250/338.2
11	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6517205	20030909	67	Semiconductor storage device and process for manufacturing the same	438/210	438/2317
12	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6599840	20030729	34	Material removal method for forming a structure	438/705	438/2357
13	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6536638	20030722	63	Material removal method for forming a structure	438/743	257/221.0

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